



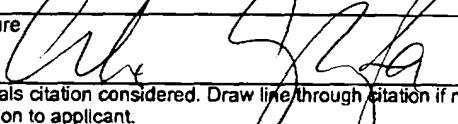
Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. 09/852,672
		Applicant Hideomi Suzawa et al.	
		Filing Date May 11, 2001	Group Art Unit 2812

Information Disclosure Statement
by Applicant
(Use several sheets if necessary)

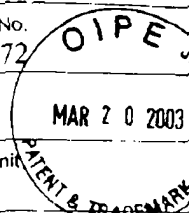
(37 CFR §1.98(b))

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							Yes	No
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Examiner Signature 	Date Considered 1/09/04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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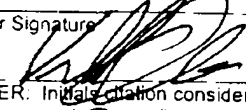
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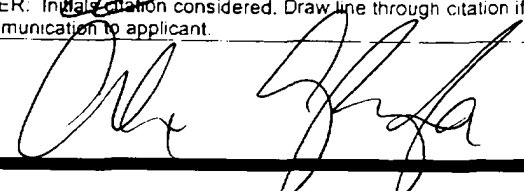
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Examiner Signature	Date Considered
	5/22/03
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Substitute Disclosure Form (PTO-1449)

 1/09/04